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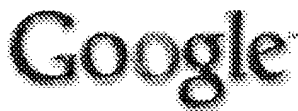
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23	BRS	1	(asynchronous adj buffer) and emulation
24	BRS	0	asynchronous adj buffer adj card
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26	BRS	0	(asynchronous adj buffer) and multiplex and emulation
27	BRS	3	(asynchronous adj buffer) and (multi-bit)
28	BRS	0	(asynchronous adj buffer) and (multi-bit) and emulation
29	BRS	0	emulation and (common near path) and multi-bit
30	BRS	267	emulation and multi-bit
31	BRS	2	emulation and multi-bit and multi-step
32	BRS	174	emulation and (digital adj logic)
33	BRS	0	emulation and (digital adj logic) and (common near path)
34	BRS	124	emulation and (digital adj logic) and path
35	BRS	26	emulation and (digital adj logic) and (multiple adj signals)
36	BRS	0	(emulation and (multiple adj signals)).ti.
37	BRS	12	(emulation and signals).ti.
38	BRS	0	(emulation and signals).ti. and (plurality near processors)
39	BRS	9	(emulation and signals).ti. and plurality
40	BRS	4	(emulation and signals).ti. and plurality and clock
41	BRS	1	(emulation and signals).ti. and plurality and clocks and path
42	BRS	4	(emulation and signals).ti. and plurality and clocks
43	BRS	0	(common and path).ti. and (digital adj logic)
44	BRS	70	(common and path).ti.
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46	BRS	0	(common and path).ti. and emulation
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49	BRS	5	(asynchronous and emulation).ti. and emulation
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52	BRS	0	(asynchronous and emulation and logic).ti.
53	BRS	11	asynchronous and (emulation and logic).ti.
54	BRS	38	(semiconductor and simulation).ti.

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55	BRS	8	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope)
56	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and scaling and bias and
57	BRS	8	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope)
58	BRS	4	(semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope)) and bias
59	BRS	0	(semiconductor and simulation).ti. and fabricating and measuring and testing
60	BRS	5	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying
61	BRS	4	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and equivalent
62	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and (equivalent near semiconductor)
63	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and (equivalent near semiconductor) and sample
64	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and (equivalent near semiconductor) and source
65	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and (equivalent near semiconductor) and FET
66	BRS	0	semiconductor and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying and FET
67	BRS	0	FET and simulation and fabricating and measuring and testing and (scanning adj electron adj microscope) and varying
68	BRS	73	FET and simulation and fabricating and measurin
69	BRS	24	FET and simulation and fabricating and measuring and testing

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70	BRS	4	FET and simulation and fabricating and measuring and testing and scaling
71	BRS	4	FET and simulation and fabricating and measuring and testing and scaling and bias
72	BRS	4	FET and simulation and fabricating and measuring and testing and scaling and bias and
73	BRS	3	MOSFET and simulation and fabricating and measuring and testing and scaling and bias and temperature

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1	BRS	21	FPGA and emulation and multiplexing and (logic adj analyzer)
2	BRS	3	FPGA and emulation and (logic adj analyzer) and (multiplexing near subsystem)
3	BRS	16	FPGA and emulation and (logic adj analyzer) and (multiplexing and subsystem)
4	BRS	15	FPGA and emulation and (logic adj analyzer) and (multiplexing and subsystem) and frequencies
5	BRS	6	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and frequencies
6	BRS	6	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and frequencies and clock
7	BRS	4	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and frequencies and clock and controller
8	BRS	3	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and (higher near frequencies) and clock and controller
9	BRS	0	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and (increase near frequencies) and clock and controller
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11	BRS	0	(FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and (higher near frequencies) and clock and controller) and lables
12	BRS	0	(FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and (higher near frequencies) and clock and controller) and
13	BRS	3	FPGA and emulation.ti. and (logic adj analyzer) and (multiplexing and subsystem) and frequencies and sampling
14	BRS	10	FPGA and emulation and (logic adj analyzer) and (multiplexing and subsystem) and frequencies and sampling
15	BRS	1	6556936.pn.
16	BRS	69	emulation near plurality
17	BRS	104	emulation adj processor
18	BRS	5	((emulation adj processor) near plurality)
19	BRS	0	((emulation adj processor) near plurality) and asynchronous
20	BRS	0	asynchronous adj buffer
21	BRS	63	asynchronous adj buffer